

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|--|--------------------------------------|------------------|---------|------------------|
| S1 | 704 | (356/614).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/11/30 15:06 |
| S2 | 34 | S1 AND defect | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/09/28 14:12 |
| S3 | 64 | (356/239.8).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/05 09:44 |
| S4 | 33 | S3 AND defect | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/09/28 14:13 |
| S5 | 10 | ("5098191" "5539514" "6052478" "6141038" "6169603" "6466315" "6541747" "6549290" "6797975" "6937754").PN. OR ("7065240"). URPN. | US-PGPUB; USPAT; USOCR | NEAR | OFF | 2006/09/28 14:14 |
| S6 | 20 | ("5267017" "5847821" "5877035" "5917588" "6028664").PN. OR ("6320655"). URPN. | US-PGPUB; USPAT; USOCR | NEAR | OFF | 2006/09/28 14:27 |
| S7 | 10 | ("5479252" "5640236").PN. OR ("5847821").URPN. | US-PGPUB; USPAT; USOCR | NEAR | OFF | 2006/09/28 14:38 |
| S8 | 3213 | ((356/614.ccls.)OR(356/237.ccls.)OR(356/239.8.ccls.)OR(356/401. ccls.)OR(356/399.ccls.)OR(356/386. ccls.)OR(356/493.ccls.)OR(356/485. ccls.)).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/09/29 14:00 |
| S9 | 1799 | ((359/894.ccls.)OR(382/145.ccls.)OR(382/144.ccls.)OR(250/201.ccls.)OR(250/559.ccls.)).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/09/29 14:04 |
| S10 | 4988 | S8 OR S9 | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/09/29 14:04 |
| S11 | 731 | S10 AND defect | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/09/29 14:05 |

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| S12 | 352 | S11 AND error | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 08:46 |
| S13 | 304985 | wafer OR reticle | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 09:16 |
| S14 | 1040937 | defect OR error OR imperfection | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 09:17 |
| S15 | 4511034 | detect\$3 OR correct\$3 OR inspect\$3 OR evaluat\$3 OR test\$3 | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 09:18 |
| S16 | 87 | locating particles | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 09:19 |
| S17 | 5259213 | S16 OR mark OR reference | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 09:19 |
| S18 | 40695 | S13 AND S14 AND S15 AND S17 | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 09:20 |
| S19 | 2618 | S13 SAME S14 SAME S15 SAME S17 | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 09:21 |
| S20 | 857 | S19 AND "356".clas. | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 09:22 |
| S21 | 9 | polystrene latex | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 14:57 |
| S22 | 2058 | PSL | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 14:57 |
| S23 | 3 | S22 NEAR poly | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 16:05 |

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| S24 | 182 | S22 AND wafer | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 16:05 |
| S25 | 353 | S22 AND semiconductor | US-PGPUB; USPAT; USOCR; JPO | NEAR | OFF | 2006/10/02 16:05 |
| S27 | 5 | laser surface particle detector | US-PGPUB; USPAT; USOCR; JPO | ADJ | OFF | 2006/10/03 15:21 |
| S28 | 7 | ("4442361" "5847821" "6122562" "6324298").PN. OR ("6559457").URPN. | US-PGPUB; USPAT; USOCR | NEAR | OFF | 2006/10/03 15:39 |
| S29 | 1865 | (356/237.2-237.5).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 08:40 |
| S30 | 22 | ("20030086080" "20050134840" "4013367" "4291990" "5076692" "5130965" "5151888" "5268747" "5506676" "5563702" "5569929" "5576825" "5602400" "5726740" "5737072" "6043932" "6084716" "6195202" "6208411" "6636301" "6850321" "6879390").PN. OR ("7075638").URPN. | US-PGPUB; USPAT; USOCR | NEAR | OFF | 2006/10/05 11:16 |
| S32 | 1867 | (356/237.2-237.5).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 08:52 |
| S33 | 707 | (356/614).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:11 |
| S34 | 65 | (356/239.8).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:12 |
| S35 | 1432 | (356/401).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:12 |
| S36 | 1005 | (356/399).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:12 |

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| S37 | 0 | (356/386).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:12 |
| S38 | 146 | (356/493).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:12 |
| S39 | 91 | (356/485).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:13 |
| S40 | 0 | (356/894).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:14 |
| S41 | 767 | (382/145).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:14 |
| S42 | 448 | (382/144).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:14 |
| S43 | 0 | (250/201).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:14 |
| S44 | 0 | (250/559).CCLS. | US-PGPUB; USPAT; USOCR; JPO | OR | OFF | 2006/10/10 16:14 |
| S45 | 0 | "wafer defect detection method" AND "inspection operation" AND "locating particles" AND "correcting error values" | US-PGPUB | NEAR | OFF | 2006/11/01 11:10 |
| S46 | 0 | "spraying a plurality of locating particles" AND "calculating offset location information" | US-PGPUB | NEAR | OFF | 2006/11/01 11:09 |
| S47 | 0 | "particle spraying unit" AND "implementing an inspection operation" AND "a particle re-detection unit" | US-PGPUB | NEAR | OFF | 2006/11/01 11:09 |
| S48 | 0 | "wafer defect detection method". clm. | US-PGPUB | NEAR | OFF | 2006/11/01 11:08 |
| S49 | 0 | "particle spraying unit".clm. | US-PGPUB | NEAR | OFF | 2006/11/01 11:09 |
| S50 | 0 | "spraying a plurality of locating particles".clm. | US-PGPUB | NEAR | OFF | 2006/11/01 11:09 |

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| S51 | 0 | "a particle re-detection unit".clm. | US-PGPUB | NEAR | OFF | 2006/11/01 11:09 |
| S52 | 18 | (raised OR grooved) WITH (fiducial mark) | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:10 |
| S53 | 2 | S52 SAME wafer | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:07 |
| S54 | 6 | S52 AND wafer | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:09 |
| S55 | 6 | S52 AND (wafer OR reticle) | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:10 |
| S56 | 6 | S52 AND (wafer OR reticle OR semiconductor) | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:11 |
| S57 | 26097 | (raised OR grooved) WITH (fiducial OR reference OR mark OR dot) | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:11 |
| S58 | 6817 | (raised OR grooved) NEAR4 (fiducial OR reference OR mark OR dot) | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:11 |
| S59 | 1071 | S58 AND (wafer OR reticle OR semiconductor) | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:11 |

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| S60 | 5479 | (raised OR grooved) NEAR4 (fiducial OR reference OR mark) | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:11 |
| S61 | 976 | S60 AND (wafer OR reticle OR semiconductor) | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:12 |
| S62 | 44 | S61 AND "356".clas. | US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB | NEAR | OFF | 2006/11/30 15:12 |